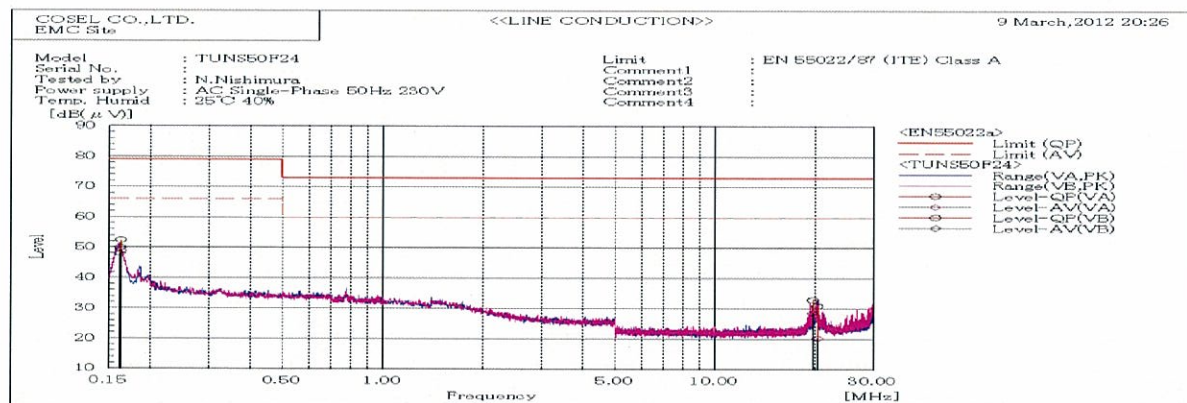
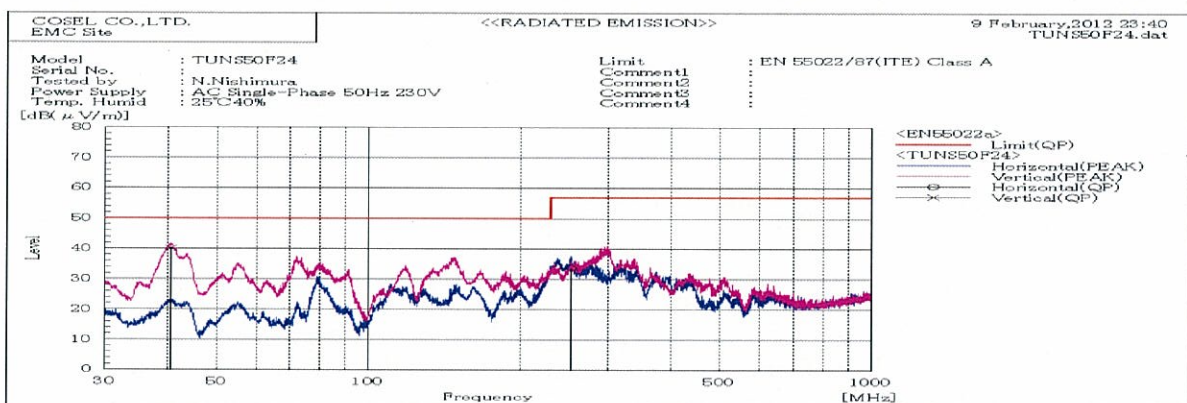


DATA SHEET		Date	17-Apr-12
Model	TUN50F24	Temp.	25 degreeC
Test	EMI	Humid.	40 %RH
	Line conduction & Radiated emission	Tested by	N.Nishimura



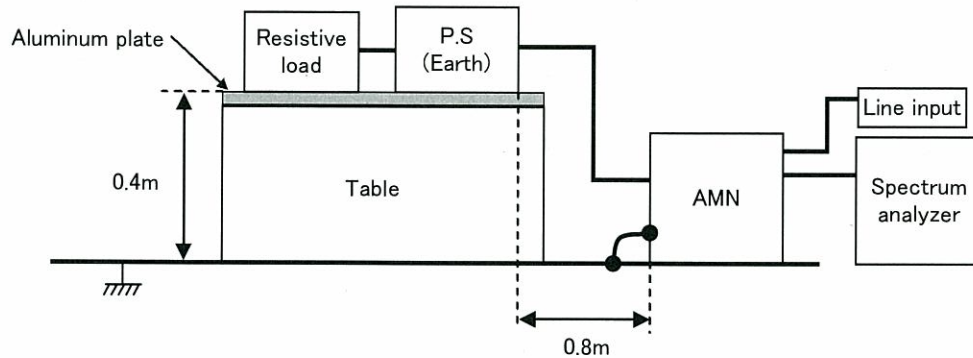
Frequency MHz	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail
		QP	AV		QP	AV	QP	AV	QP	AV	
0.16222	VB	39.7	37.7	10.2	49.9	47.9	79	66	29.1	18.1	Pass
0.16323	VA	42.1	38.7	10.2	52.3	48.9	79	66	26.7	17.1	Pass
19.6581	VB	22	17.8	10.9	32.9	28.7	73	60	40.1	31.3	Pass
20.30295	VA	19.9	9.3	11	30.9	20.3	73	60	42.1	39.7	Pass



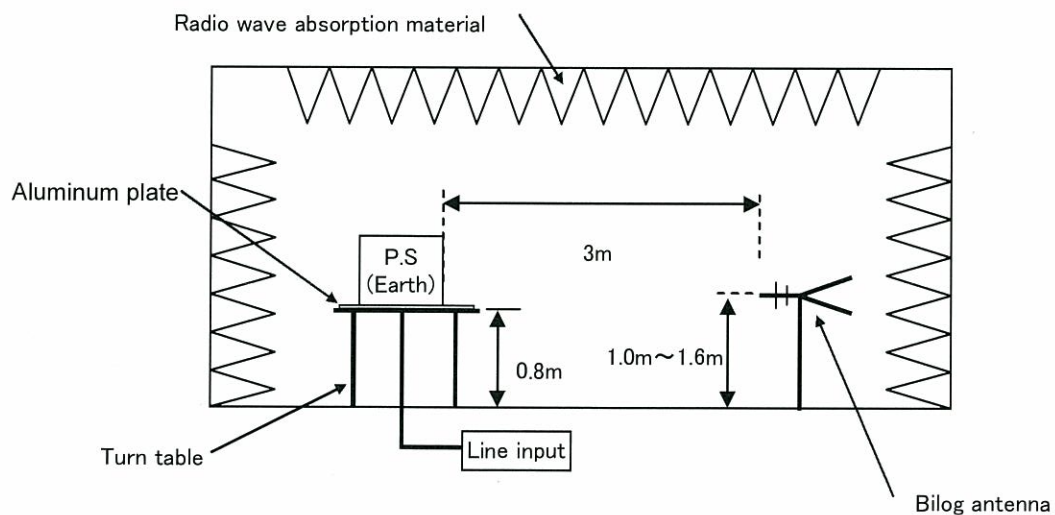
Frequency MHz	Polarization	Stability	Reading dB(uV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Height cm	Angle deg	Pass/ Fail
			QP		QP	QP	QP			
40.588	V	Stable	55.7	-15.6	40.1	50	9.9	105	48	Pass
252.941	H	Stable	52	-18.3	33.7	57	23.3	126	144	Pass

DATA SHEET		Date	17-Apr-12
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	N.Nishimura

## 1. Line conduction



## 2. Radiated emission

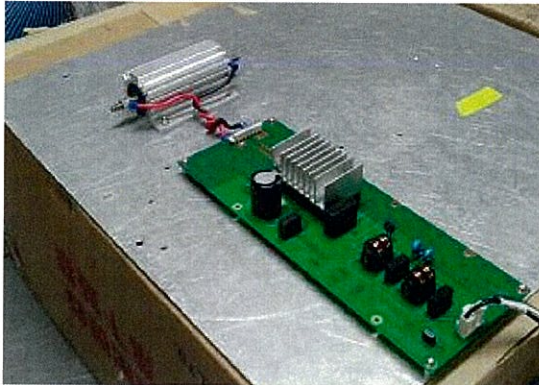


Test: EMI

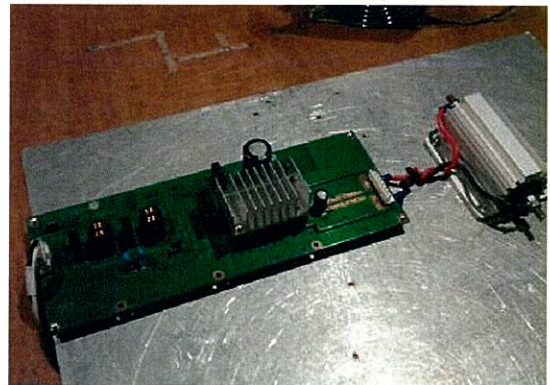
Model Name: TUNS50F Series

## ○ Photographs of Test Set-Up

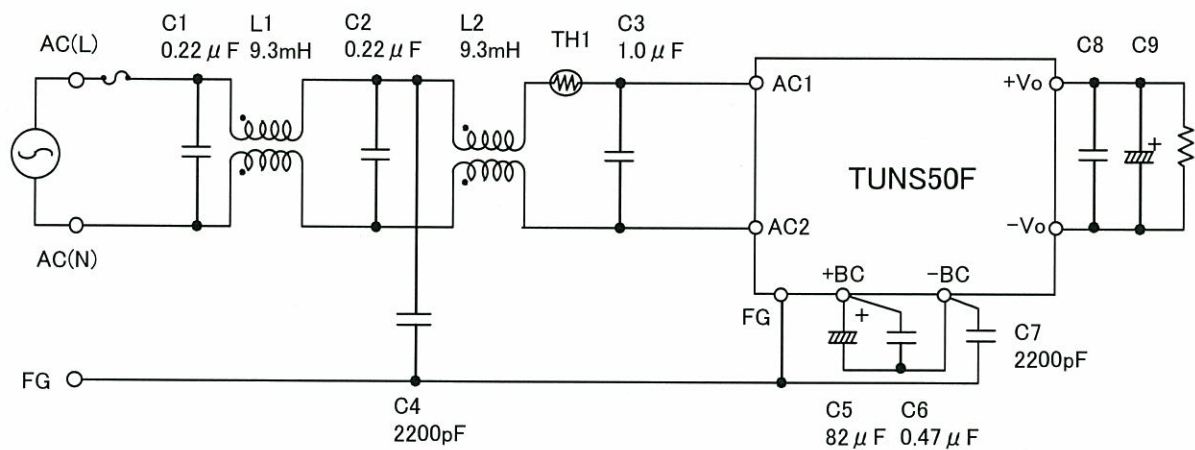
### LINE CONDUCTION



### RADIATED EMISSION



## ○ Test circuit



L1,L2 : SS11VL-R10093(NEC TOKIN)

TH1 : 5D2-08(SEMITEC)

C8 : TUNS50F05 10 μF

TUNS50F12 10 μF

TUNS50F24 4.7 μF

C9 : TUNS50F05 2200 μF

TUNS50F12 470 μF

TUNS50F24 220 μF